Notice of Allowability	Application No.	Applicant(s)
	09/512,570	CONRAD ET AL.
	Examiner	Art Unit
	Tom Y Lu	2621
The MAILING DATE of this communication appe All claims being allowable, PROSECUTION ON THE MERITS IS herewith (or previously mailed), a Notice of Allowance (PTOL-85) NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RI of the Office or upon petition by the applicant. See 37 CFR 1.313	(OR REMAINS) CLOSED or other appropriate comm GHTS. This application is	in this application. If not included nunication will be mailed in due course. THIS
1. $igspace$ This communication is responsive to <u>the amendment filed</u> of	on 07/21/2004.	
2. X The allowed claim(s) is/are 1.2.4-7.9-12 and 14-21.		
3. $igotimes$ The drawings filed on <u>24 February 2004</u> are accepted by the	ne Examiner.	
4. Acknowledgment is made of a claim for foreign priority una) All b) Some* c) None of the: 1. Certified copies of the priority documents have 2. Certified copies of the priority documents have 3. Copies of the certified copies of the priority documents have International Bureau (PCT Rule 17.2(a)). * Certified copies not received: Applicant has THREE MONTHS FROM THE "MAILING DATE" noted below. Failure to timely comply will result in ABANDONM THIS THREE-MONTH PERIOD IS NOT EXTENDABLE. 5. A SUBSTITUTE OATH OR DECLARATION must be submit INFORMAL PATENT APPLICATION (PTO-152) which give 6. CORRECTED DRAWINGS (as "replacement sheets") must (a) including changes required by the Notice of Draftspers 1) hereto or 2) to Paper No./Mail Date	e been received. been received in Application cuments have been received of this communication to fill ENT of this application. itted. Note the attached EX es reason(s) why the oath of the submitted. con's Patent Drawing Reviews Amendment / Comment of the header according to 37 C sit of BIOLOGICAL MAT	ion Noed in this national stage application from the ed in this national stage application from the ed in this national stage application from the ear reply complying with the requirements CAMINER'S AMENDMENT or NOTICE OF or declaration is deficient. EW (PTO-948) attached or in the Office action of the drawings in the front (not the back) of FR 1.121(d). TERIAL must be submitted. Note the
Attachment(s) 1. ☑ Notice of References Cited (PTO-892) 2. ☐ Notice of Draftperson's Patent Drawing Review (PTO-948) 3. ☐ Information Disclosure Statements (PTO-1449 or PTO/SB/0 Paper No./Mail Date 4. ☐ Examiner's Comment Regarding Requirement for Deposit of Biological Material	6. ☐ Interview S Paper No 8), 7. ☐ Examiner's 9. ☐ Other	Informal Patent Application (PTO-152) Summary (PTO-413), Mail Date S Amendment/Comment S Statement of Reasons for Allowance LEO BOUDREAU PERVISORY PATENT EXAMINER TECHNIOLOGY CENTER 2600

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DETAILED ACTION

Response to Amendment

- 1. The Request for Continued Examination filed on July 21, 2004 has been entered.
- 2. Upon entry of the Request for Continued Examination, the amendment filed on July 21, 2004 has been entered.
- 3. Claims 3, 8 and 13 were cancelled.
- 4. Claims 1, 6 and 11 are amended.
- 5. Claims 1-2, 4-7, 9-12 and 14-21 are pending.

Response to Arguments

6. Applicant's arguments, see Remarks, pages 8-12, filed on July 21, 2004, with respect to Claims 1, 6 and 11 have been fully considered and are persuasive. The rejection of Claims 1, 6 and 11 has been withdrawn.

Allowable Subject Matter

7. Claims 1-2, 4-7, 9-12 and 14-21 are allowed.

The following is an examiner's statement of reasons for allowance:

a. Independent Claims 1, 6 and 11 define features of using a photolithography process to form a submicron structure on a semiconductor wafer; forming an electron beam image of said structure on a two-dimensional array of pixels, wherein said image has a shape; identifying a more precise edge of the image shape by obtaining intensity vs. pixel information along a plurality of scans extending in different direction, through substantially a point along a preliminary, approximate edge of the image shape; detecting a point on the more precise edge

location of the image by subjecting the recognized scans to an edge detection algorithm. These features in combination with other feature in Claims 1, 6 and 11, which are the broadest allowable claims, are not taught or suggested by the art of record.

- b. Claims 2, 4-5, 16 and 17 are dependent upon Claim 1.
- c. Claims 7, 9-10, 18 and 19 are dependent upon Claim 6.
- d. Claims 12, 14-15, 20 and 21 are dependent upon Claim 11.
- 8. Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Conclusion

- 9. The prior art made of record and not relied upon is considered pertinent to applicant's disclosure.
 - a. Tessadra, U.S. Patent Application Publication No. 2003/0095710 A1, see Paragraph 0090.
 - b. Ausschnitt et al, U.S. Patent No. 5,914,784, see abstract, figure 6, and column 6.
- 10. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Tom Y Lu whose telephone number is (703) 306-4057. The examiner can normally be reached on 8:30AM-5PM.

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If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Leo H Boudreau can be reached on (703) 305-4706. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Tom Y. Lu

LEU BOUDREAU

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